

Introduction to Quantum Metrology

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Quantum Standards and Instrumentation

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Preface

Quantum metrology is a field of theoretical and experimental study of high-resolution and high-accuracy methods for measurement of physical quantities based on quantum mechanics, particularly using quantum entanglement. Without equivalent in classical mechanics, quantum entanglement of particles or other quantum systems is an unusual phenomenon in which the state of a system can be determined better than the state of its parts. Attempts are made to use new measurement strategies and physical systems in order to attain measurement accuracy never achieved so far.

Quantum metrology sprang into existence at the beginning of the twentieth century, along with quantum mechanics. After all, the Heisenberg uncertainty principle, together with the Schrödinger equation and the Pauli exclusion principle constituting the basis of the formalism of quantum mechanics, is also the fundamental equation of quantum metrology. The uncertainty principle sets limits to measurement accuracy, but has no relation to the technical realization of the measurement.

Quantum metrology only started to develop in the latter half of the twentieth century, following the discovery of phenomena of fundamental importance to this field, such as the Josephson effect, the quantum Hall effect or the tunneling of elementary particles (electrons, Cooper pairs) through a potential barrier. Using new important physical advances, quantum metrology also contributes to progress in physics. In the past 50 years the Nobel Prize was awarded for 16 achievements strongly related to quantum metrology. In 1964 Townes, Basov and Prokhorov received the Nobel Prize *for fundamental work in the field of quantum electronics, which has led to the construction of oscillators and amplifiers based on the maser-laser principle*. Presently masers constitute a group of atomic clocks, installed in metrology laboratories as well as on satellites of GPS and GLONASS navigation systems. Gas lasers are basic instruments in interferometers used in metrology of length, and semiconductor lasers are used in industrial measurements. Haroche and Wineland were awarded the Nobel Prize in 2012 *for ground-breaking experimental methods that enable measuring and manipulation of individual quantum systems*, that is, for studies in the field of quantum metrology. In 1964–2012 the Nobel Prize was awarded for important discoveries such as *the Josephson effect* (Josephson

by BIPM. As an academic textbook it propagates a new approach to metrology, with more emphasis laid on its connection with physics, which is of much importance for the constantly developing technologies, particularly nanotechnology.

Large parts of this publication represent a translation from my book *Introduction to Quantum Metrology* published in Polish by Publishing House of Poznan University of Technology in 2007 and used here in translation with the publisher's permission.

I thank all those who helped me collect material for this book. Special thanks go to my colleagues at the Polish Central Office of Measures in Warsaw and at Physikalisch-Technische Bundesanstalt in Braunschweig.

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Chapter 1

Theoretical Background of Quantum Metrology

Abstract This chapter outlines the history of quantum mechanics and presents its fundamental formulas: the Schrödinger equation with the interpretation of the wave function, the Pauli exclusion principle, and the Heisenberg uncertainty principle. The latter is illustrated with sample numerical calculations. We briefly discuss the application of quantum effects in metrology, and present and compare the limits of accuracy and resolution of classical and quantum standards. Prospects for a new system of units are discussed as well.

1.1 Introduction

Measurement consists in comparing the measured state A_x of a quantity to its state A_{ref} considered a reference state, as shown schematically in Fig. 1.1. Thus, the accuracy of the measurement cannot be better than the accuracy of the standard.

For many years metrologists have been working on the development of standards that would only depend on fundamental physical constants and atomic constants. With such standards units of measurement can be realized on the basis of quantum phenomena. One of the directions of research in metrology is the creation of a new system of measurement, based on a set of quantum and atomic standards, that would replace the classical SI system.

In the present chapter we shall focus on measures and the development of the system of units of measurement. We shall discuss the history of measurement standards and present in detail the currently used International System of Units (SI). The set of the base units of the SI system of measurement will be discussed as well. The following chapters present the quantum phenomena that are the most commonly used in metrology: the Josephson effect is discussed in Chap. 4, the quantum Hall effect in Chap. 6, and the tunneling of single electrons in Chap. 8. These three phenomena are considered of particular importance not only for electrical metrology,

